

OptiMOS[™] Power-Transistor

Features

- Optimized for high performance SMPS, e.g. sync. rec.
- 100% avalanche tested
- Superior thermal resistance
- N-channel
- Qualified according to JEDEC¹⁾ for target applications
- · Pb-free lead plating; RoHS compliant
- Halogen-free according to IEC61249-2-21







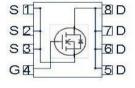
Product Summary

V_{DS}	60	V
$R_{\mathrm{DS(on),max}}$	10	mΩ
I _D	40	Α
Q _{OSS}	14	nC
Q _G (0V10V)	12	nC

PG-TSDSON-8 (Fused Leads)



Туре	Package	Marking
BSZ100N06NS	PG-TSDSON-8 (Fused Leads)	100N06N



Maximum ratings, at T_i =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	ID	V _{GS} =10 V, T _C =25 °C	40	А
		V _{GS} =10 V, T _C =100 °C	29	
		$V_{\rm GS}$ =10 V, $T_{\rm C}$ =25 °C, $R_{\rm thJA}$ =60K/W ²⁾	11	
Pulsed drain current ³⁾	I _{D,pulse}	T _C =25 °C	160	
Avalanche energy, single pulse ⁴⁾	E _{AS}	$I_{\rm D}$ =20 A, $R_{\rm GS}$ =25 Ω	19	mJ
Gate source voltage	V_{GS}		±20	V

¹⁾ J-STD20 and JESD22

²⁾ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm² (one layer, 70 μm thick) copper area for drain connection. PCB is vertical in still air.

³⁾ See figure 3 for more detailed information

⁴⁾ See figure 13 for more detailed information



Maximum ratings, at T_j =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Power dissipation	P_{tot}	T _C =25 °C	36	W
		T _A =25 °C, R _{thJA} =60 K/W ²⁾	2.1	
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 150	°C
IEC climatic category; DIN IEC 68-1			55/150/56	

Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	

Thermal characteristics

Thermal resistance, junction - case	R_{thJC}	bottom	-	-	3.5	K/W
Device on PCB	R_{thJA}	6 cm ² cooling area ²⁾	-	1	60	

Electrical characteristics, at T_j =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	$V_{(BR)DSS}$	V _{GS} =0 V, I _D =1 mA	60	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}=V_{\rm GS}, I_{\rm D}=14~\mu{\rm A}$	2.1	2.8	3.3	
Zero gate voltage drain current	I _{DSS}	$V_{\rm DS} = 60 \text{ V}, V_{\rm GS} = 0 \text{ V}, $ $T_{\rm j} = 25 \text{ °C}$	1	0.1	1	μΑ
		V _{DS} =60 V, V _{GS} =0 V, T _j =125 °C	-	10	100	
Gate-source leakage current	I _{GSS}	$V_{\rm GS}$ =20 V, $V_{\rm DS}$ =0 V	-	10	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	V _{GS} =10 V, I _D =20 A	-	8.5	10	mΩ
		V _{GS} =6 V, I _D =5 A	-	12.4	15	
Gate resistance	R _G		-	1.1	1.7	Ω
Transconductance	g_{fs}	$ V_{\rm DS} > 2 I_{\rm D} R_{\rm DS(on)max},$ $I_{\rm D} = 20~{\rm A}$	16	33	-	S



Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C _{iss}		-	860	1075	pF
Output capacitance	Coss	V_{GS} =0 V, V_{DS} =30 V, f=1 MHz	-	210	263	
Reverse transfer capacitance	C _{rss}		-	16	32	
Turn-on delay time	$t_{d(on)}$		-	6	-	ns
Rise time	t _r	V _{DD} =30 V, V _{GS} =10 V,	-	2	-	
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =20 A, $R_{\rm G,ext}$ =1.6 Ω	-	10	-	
Fall time	t _f]	-	2	-	
Gate Charge Characteristics ⁵⁾						
Gate to source charge	Q _{gs}		-	4.1	-	nC
Gate charge at threshold	Q _{g(th)}		-	2.4	-	
Gate to drain charge	Q _{gd}	V _{DD} =30 V, I _D =20 A,	-	2.5	3.7	
Switching charge	Q _{sw}	V _{GS} =0 to 10 V	-	4.2	-	
Gate charge total	Qg		-	12	15	
Gate plateau voltage	V _{plateau}		-	4.8	-	V
Gate charge total, sync. FET	Q _{g(sync)}	V _{DS} =0.1 V, V _{GS} =0 to 10 V	-	10	-	nC
Output charge	Q _{oss}	V _{DD} =30 V, V _{GS} =0 V	-	14	-	
Reverse Diode						
Diode continuous forward current	Is	T -25 °C	-	-	30	А
Diode pulse current	I _{S,pulse}	− T _C =25 °C	-	-	160	
Diode forward voltage	V _{SD}	V _{GS} =0 V, I _F =20 A, T _j =25 °C	-	0.92	1.2	V
Reverse recovery time	t _{rr}	V _R =30 V, I _F =20 A,	-	33	53	ns
Reverse recovery charge	Q _{rr}	di _F /dt=100 A/µs	-	30	-	nC

 $^{^{5)}}$ See figure 16 for gate charge parameter definition



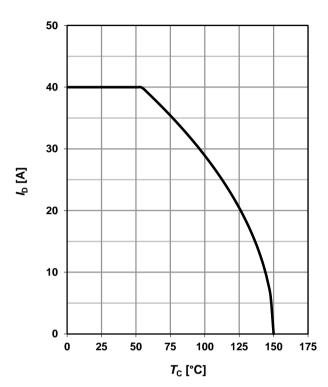
1 Power dissipation

$P_{\text{tot}} = f(T_{\text{C}})$

30 20 10 0 25 50 75 100 125 150 175 T_C [°C]

2 Drain current

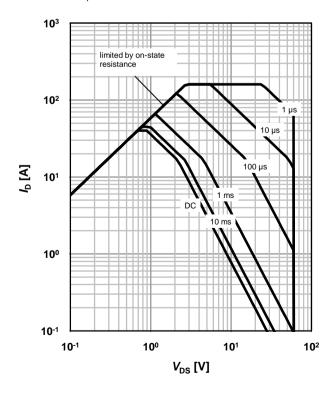
$$I_D=f(T_C); V_{GS} \ge 10 \text{ V}$$



3 Safe operating area

 $I_D=f(V_{DS}); T_C=25 \text{ °C}; D=0$

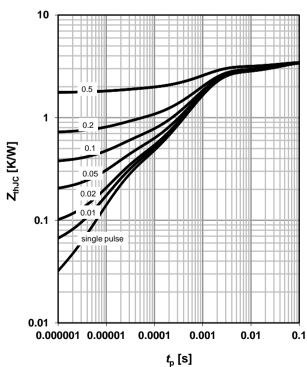
parameter: t_p



4 Max. transient thermal impedance

 Z_{thJC} =f(t_{p})

parameter: $D=t_p/T$

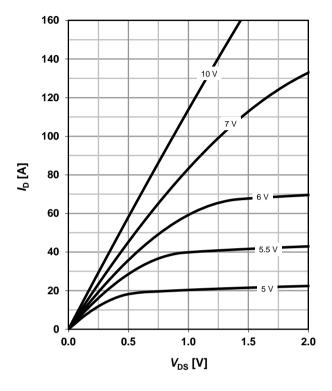




5 Typ. output characteristics

 $I_D=f(V_{DS}); T_j=25 °C$

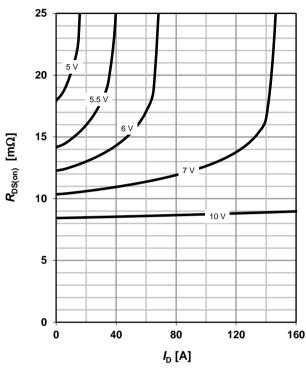
parameter: V_{GS}



6 Typ. drain-source on resistance

 $R_{DS(on)}=f(I_D); T_j=25 \text{ °C}$

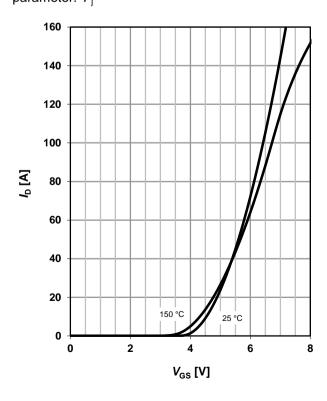
parameter: V_{GS}



7 Typ. transfer characteristics

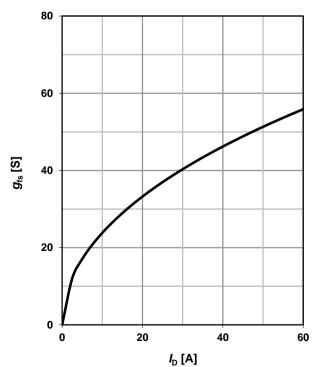
 $I_{D}=f(V_{GS}); |V_{DS}|>2|I_{D}|R_{DS(on)max}$

parameter: T_i



8 Typ. forward transconductance

$$g_{fs}$$
=f(I_D); T_j =25 °C



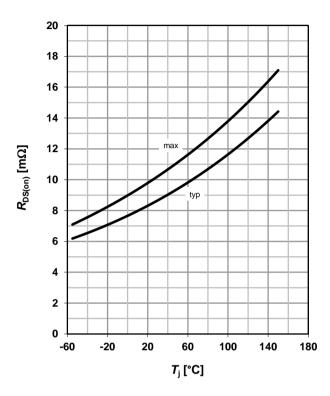


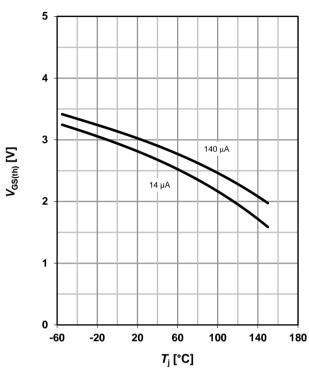
9 Drain-source on-state resistance

$R_{DS(on)} = f(T_i); I_D = 20 \text{ A}; V_{GS} = 10 \text{ V}$

10 Typ. gate threshold voltage

$$V_{GS(th)} = f(T_i); V_{GS} = V_{DS}$$





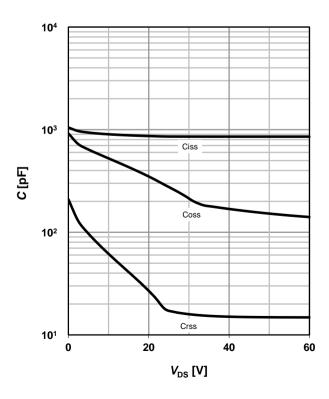
11 Typ. capacitances

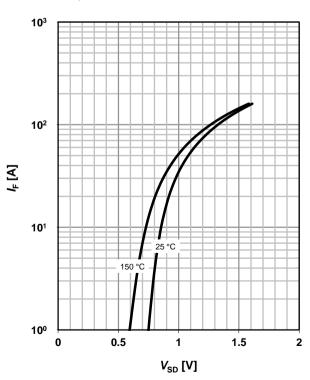
$$C=f(V_{DS}); V_{GS}=0 V; f=1 MHz$$

12 Forward characteristics of reverse diode

$$I_{\mathsf{F}} = \mathsf{f}(V_{\mathsf{SD}})$$

parameter: $T_{\rm j}$



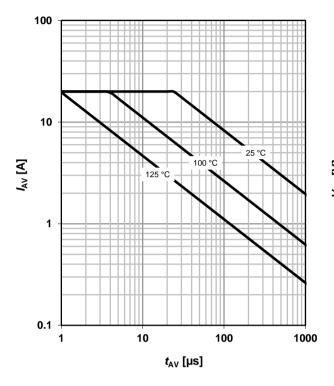




13 Avalanche characteristics

 I_{AS} =f(t_{AV}); R_{GS} =25 Ω

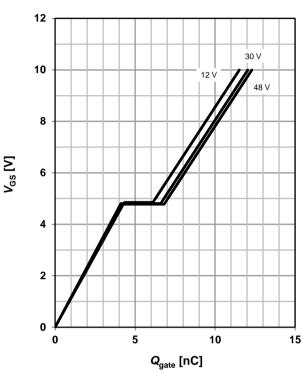
parameter: $T_{j(start)}$



14 Typ. gate charge

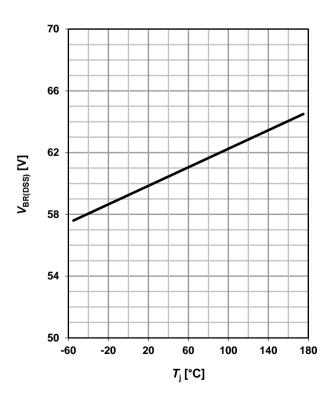
 V_{GS} =f(Q_{gate}); I_D =20 A pulsed

parameter: $V_{\rm DD}$

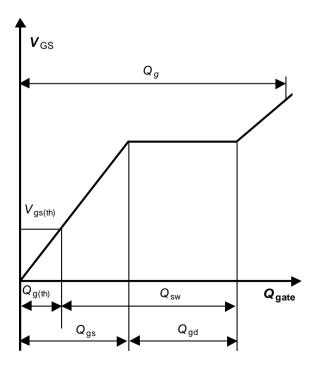


15 Drain-source breakdown voltage

 $V_{BR(DSS)}=f(T_j); I_D=1 \text{ mA}$

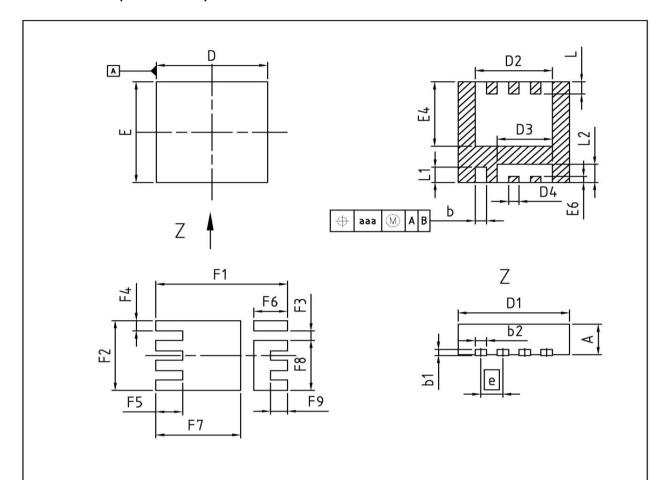


16 Gate charge waveforms

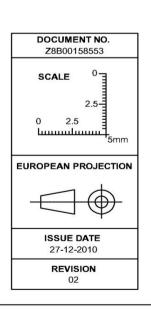




PG-TSDSON-8 (Fused Leads): Outline



DIM r	MILLIM	ETERS	INC	HES	
DIWI	MIN	MAX	MIN	MAX	
Α	0.90	1.10	0.035	0.043	
b	0.24	0.44	0.009	0.017	
b1	0.10	0.30	0.004	0.012	
b2	0.24	0.44	0.009	0.017	
D=D1	3.20	3.40	0.126	0.134	
D2	2.19	2.39	0.086	0.094	
D3	1.54	1.74	0.061	0.069	
D4	0.21	0.41	0.008	0.016	
E	3.20	3.40	0.126	0.134	
E4	2.01	2.21	0.079	0.087	
E6	0.10	0.30	0.004	0.012	
е	0.65 (BSC)		0.0	026 (BSC)	
N		8	8		
L	0.30	0.51	0.012	0.020	
L1	0.40	0.70	0.016	0.028	
L2	0.50	0.70	0.020	0.028	
aaa	0.2	25	0.0)10	
F1	3.9	90	0.154		
F2	2.2	29	0.090		
F3	0.3	31	0.012		
F4	0.34		0.013		
F5	0.80		0.031		
F6	1.00		0.039		
F7	2.51		0.099		
F8	1.64		0.065		
F9	0.5	50	0.020		





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